Delving into the Mind of Indian Serial Killers-A Retrospective Review Study

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Abstract:

It is assumed that "No one is innate offender", there remains extrinsic or intrinsic factors which triggers or results into violent behaviour. To advocate the statement we aim at scrutinizing various extrinsic factors such as education, socio-economic standards and cultural background of famous serial killers of India which ensue in their irrational and vicious behaviour. This is achieved by focusing light on their life history via different case studies. A comparative study is done to conclude the modus operandi opted by these offender and to answer "Why", the particular method have been implied.

It further focus on what factor triggers such conduct and how law enforcement agencies can work on captivating strategies as serial offenders have less likelihood of getting tracked down because of their high intellect. Criminal profiling can be proved useful in such cases as after behavioral study brings in light the unconnected incidents together like missing piece of jig-saw. This criminal profiling at the end strengthens law enforcement agencies.

Biography:

He is M.Sc. (Phys), Ph.D. (Material Sc.) M. Sc. (Psychology) qualified expert having 12 years of experience in the field of forensic science and crime scene investigation. He has been awarded many a times at National and International Level. He has published more than 135 research article and 08 books in various fields of Physics and forensic sciences. He has visited 625 Crime Scene and reported 600 cases of Physics Div, State Forensic Science Lab, Jaipur (Raj.) India. He has delivered various Invited talks in National and International Conferences in India and also having experience of teaching PG course in Forensic as Guest speaker at NICFS, New Delhi. . Cyber Crime, Digital Forensic, Reconstruction of Crime Scene, Crime Scene Investigation, Trace Evidence Analysis and XRF, EDX measurements.